

Application/Control No.	Applicant(s)/Patent under Reexamination							
09/527,855	KADAMBI ET AL.							
Examiner	Art Unit							
Hanh Nauvon	2662							

					Hanh Nguyen 2662																
								18	SSU	E C	LAS	SIF	ICA ⁻	ΓΙΟΝ	1						
			OR	GINA	AL.		T							CROSS		RENCE(S)				
CLASS SUBCLASS						CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)													
370 394				370	3	96	35	8	391	1											
INTERNATIONAL CLASSIFICATION																					
н	0	4	L		12/	28															
н	0	4	L		12/	50															
					/	•	[_														
						•															
					/	•															
	~	(As	sista	nt Ex	amine	r) ([Date)	ž.	Hi	Igny	<i>f</i> lr	, , ,	HAI PRIMA	NH NO	SUYE	NED	Tota	l Clai	ms Alle	owed:	4
(Legalynstruments Examiner) Date					15	HANH NGUYEN PRIMARY EXAMINE Hanh Nguyen 9/12/05 (Primary Examiner) (Date)								O.G. Print Claim(s)			O.G. Print Fig.				
{	7		J													L			56		
					ne orde	e order as presented by applicant						PA	ļ:	<u> </u>			□ R.				
- C	<u> </u>	Original			Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1		1																	1		
3		3	-				-			-			-								
- 2		4	٦!!!!	-									-								_
					- 1																
			-	-						-			-								
	+		-	-				-		-			-						1		
	_		4	-																	
	+		-	_															-		<u> </u>
]																1		
	<u> </u>		-	-																	ļ
	\dashv		1	-															-		
			4	-																	
	+		-	-								_							-		<u> </u>
																			1		
	\bot		4	Į]		
	-		-	ŀ															-		
]																		
	1]																1		
_	+		-	-															<u> </u>		
	+		1	-															-		
			1	-															1	-	